

<b>Notice of References Cited</b>	Application/Control No. 09/929,326	Applicant(s)/Patent Under Reexamination TAMAYAMA, RYUZO	
	Examiner Devona E. Faulk	Art Unit 2644	Page 1 of 1

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	C	US-			
	D	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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